

Innovalia Association is proud to present the 21st edition Conference Programme of Metromeet, the leading Conference on Industrial Dimensional Metrology.

Metromeet gathers Quality Management Professionals and lead companies that will bring you the latest news about Digital and Optical developments, metrological software or calibration standards among other topics. Metromeet also offers a complete and interesting Conference Programme which will help you to improve the quality and efficiency of your products and industrial processes.

TUTORIALS



Toni Ventura-Traveset CEO at Datapixel

Toni is a Telecommunications Engineer, founder and General Manager of DATAPIXEL in Spain. Specialized Technological Consultant for CARSA. He is Member of the Executive Committee of the European Machine Vision Association (EMVA) and of some international committees working on standards like the OSIS committee (Optical Sensor Interface Standard) of the ia.cmm. Former Manager of the Computer Vision Centre (CVC). Author of a great variety of technical papers and seminars in Computer Vision, Image Processing, 3D Vision and Virtual Metrology for the industrial and medical areas.



Edward Morse
Director of UNC Charlotte's Center
for Precision Metrology

Edward Morse is the Director of the Center for Precision Metrology at UNC Charlotte and the Norvin Kennedy Dickerson Jr. Distinguished Professor of Mechanical Engineering. He chairs ASME's B89 Committee on Dimensional Metrology and serves as the U.S. representative to ISO Technical Committee 213 on Geometric Product Specification and Verification.

October 16

00:30 00:00	Docietystian I Coffee
08:30 - 09:00	Registration + Coffee
09:00 - 09:15	OPENING
	Jesús de La Maza President of Innovalia Group
09:15 - 12:10	TUTORIAL
	Al-Manufacturing Toni Ventura CEO at Datapixel, Spain
12:10 - 12:40	Coffee Break
12:40 - 14:00	TRACK 1: Metrology for Materials and Sustainability
12:40 - 13:20	Methodologies for Metrological Evaluation of Polymeric AM Parts by XCT José A. Yagüe Fabra Dean of the School of Engineering and Architecture at University of Zaragoza, Spain
13:20 - 14:00	Information Modelling for the Digital & Green Transition Dimitris Kyritsis Professor Emeritus of ICT for Sustainable Manufacturing at EPFL, Switzerland, Senior Advisor at University of Oslo, Norway
14:00 - 15:30	Lunch
15:30 - 16:30	KEYNOTE
	The Digital Transformation of Metrology: Shaping the Future of Quality Documentation Thomas Engel Research Scientist at Siemens, Germany
16:30 - 17:50	TRACK 2: Al-Driven Verification and Quality Assurance
16:30 - 17:10	Leveraging Al for Smarter Verification in Legal Metrology Lalit Harode Joint Controller at Legal Metrology Organization, India
17:10 - 17:50	Redefining Dimensional Quality: Measurement at the Heart of the Process Ainhoa Etxabarri Engineer at Innovalia Metrology, Spain
20:30 - 23:00	Dinner Sociedad Bilbaina

^{*}The organization reserves the right to reschedule, add or cancel presentations.

October 17

08:30 - 09:00	Registration + Coffee
09:00 - 11:30	TUTORIAL
	The Practical Application of Decision Rules Edward Morse Director of UNC Charlotte's Center for Precision Metrology, USA
11:30 - 12:00	Coffee Break
12:00 - 13:20	TRACK 3: From Data to Decision: Visualization and Smart Control
12:00 - 12:40	ASE: A No Code Framework for Smart Quality Control Claudio Turrin Senior Quality Assurance Automation Engineer at SMC Automation, Italy
12:40 - 13:20	Trusted data exchange for excellence in metrology services Dr. Óscar Lázaro Managing Director at Innovalia Association, Spain
13:20 - 14:50	Lunch
14:50 - 16:10	TRACK 4: Digital Twins and Smart Robotics in Metrology
14:50 - 15:30	Digital Metrological Twin for 3D Robotic Scanning System Ahmed Chekh Oumar Precision Engineering Researcher at Tekniker, Spain
14:50 - 15:30 15:30 - 16:10	Digital Metrological Twin for 3D Robotic Scanning System
	Digital Metrological Twin for 3D Robotic Scanning System Ahmed Chekh Oumar Precision Engineering Researcher at Tekniker, Spain Enhancing On-machine Laser-scanner Measurements through Predicted Reflected Point Intensity
15:30 - 16:10	Digital Metrological Twin for 3D Robotic Scanning System Ahmed Chekh Oumar Precision Engineering Researcher at Tekniker, Spain Enhancing On-machine Laser-scanner Measurements through Predicted Reflected Point Intensity Guillermo González Marín Engineer at CFAA, Spain
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